

ABSTRACT

An inspection system, including: at least one ray source (100) rotatable between at least two scanning positions around a rotation axis, and a rotation angle of at least one ray source between two adjacent scanning positions is greater than an angle of adjacent target spots of each ray source (100) relative to the rotation axis; a detector assembly (200), and a conveying device (300) configured to carry an object to be inspected. At least one ray source (100) and the detector assembly (200) are movable in a traveling direction relative to the conveying device (300), so that the object (10) to be inspected may enter an inspection region (30). When at least one ray source (100) is located at one of scanning positions, at least one ray source (100) and the detector assembly (200) move in the traveling direction relative to the conveying device (300) and at least one ray source (100) emits X-rays; after at least one ray source (100) and the detector assembly (200) move a predetermined distance in the traveling direction relative to the conveying device (300), at least one ray source (100) rotates around the rotation axis to another of scanning positions.